

Appl. No. 10/672,655
Amdt. dated December 30, 2004
Reply to Office action of July 13, 2004

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1(currently amended). A probe assembly for probing an electrical device, said probe assembly comprising:

(a) a chuck having a first conductive member with a surface suitable for supporting an electrical device; and

(b) a second conductive member spaced apart from said chuck, wherein said surface is capable of supporting said electrical device at a location is spaced between said first conductive member and said second conductive member, wherein said ~~first conductive member surface~~ is electrically interconnected to said second conductive member, ~~wherein said first conductive member and said second conductive member are electrically connected to the same potential.~~

2(original). The probe assembly of claim 1 wherein said second conductive member is electrically interconnected to a test signal of said electrical device.

3(original). The probe assembly of claim 1 wherein said first conductive member comprises a first plate, said second conductive member comprises a second plate, and wherein said second conductive member is spaced further distant from said electrical device than said first conductive member.

4(original). The probe assembly of claim 1 wherein said second conductive member comprises a second plate and is vertically spaced apart from said first conductive member.

5(original). The probe assembly of claim 1 wherein said second conductive member is electrically interconnected to said ~~first conductive member~~ surface completely within an environmental chamber.

6(original). The probe assembly of claim 1 wherein said second conductive member is free from being supported by said chuck.

7(original). The probe assembly of claim 1 wherein said first conductive member is electrically interconnected to a first probe, wherein said second conductive member is electrically interconnected to a second probe.

8(original). The probe assembly of claim 1 wherein said first conductive member and said second conductive member are electrically interconnected to a first probe.

9(currently amended). The probe assembly of claim 1 wherein said first conductive member is electrically interconnected to a first probe and wherein said first probe is electrically interconnected to test instrumentation using a conductive element having a length, at least 50% of said length comprising a twisted pair of wires ~~over at least 50% of the distance between said first probe and said test instrumentation~~.

10(original). The probe assembly of claim 1 further comprising a detachable substantially closed loop member engageable with said first conductive member and said second

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conductive member, where said loop member includes a flexible member interconnecting said first conductive member and said second conductive member.